

MOS FIELD EFFECT TRANSISTOR μ PA1856

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1856 is a switching device which can be driven directly by a 2.5-V power source.

The μ PA1856 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

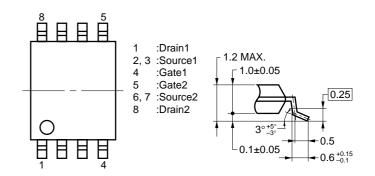
- Can be driven by a 2.5-V power source
- · Low on-state resistance

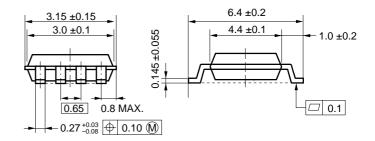
$$\begin{split} &R_{DS(on)1} = 45 \text{ m}\Omega \text{ MAX. (VGs} = -4.5 \text{ V, ID} = -2.5 \text{ A)} \\ &R_{DS(on)2} = 48 \text{ m}\Omega \text{ MAX. (VGs} = -4.0 \text{ V, ID} = -2.5 \text{ A)} \\ &R_{DS(on)3} = 72 \text{ m}\Omega \text{ MAX. (VGs} = -2.7 \text{ V, ID} = -2.5 \text{ A)} \\ &R_{DS(on)4} = 77 \text{ m}\Omega \text{ MAX. (VGs} = -2.5 \text{ V, ID} = -2.5 \text{ A)} \end{split}$$

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1856GR-9JG	Power TSSOP8

PACKAGE DRAWING (Unit: mm)

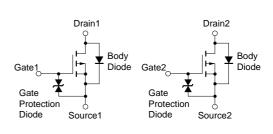




ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

	-		
Drain to Source Voltage	VDSS	-20	V
Gate to Source Voltage	Vgss	±12	V
Drain Current (DC)	ID(DC)	±4.5	Α
Drain Current (pulse) Note1	D(pulse)	±18	Α
Total Power Dissipation Note2	Рт	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

EQUIVALENT CIRCUIT



- **Notes 1.** PW \leq 10 μ s, Duty Cycle \leq 1 %
 - 2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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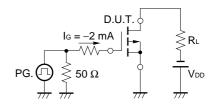
ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	Vps = -20 V, Vgs = 0 V			-10	μΑ
Gate Leakage Current	lgss	Vgs = ±12 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$	-0.5	-1.1	-1.5	V
Forward Transfer Admittance	yfs	$V_{DS} = -10 \text{ V}, I_{D} = -2.5 \text{ A}$	3	8.8		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = -4.5 V, ID = -2.5 A		37	45	mΩ
	RDS(on)2	Vgs = -4.0 V, ID = -2.5 A		39	48	mΩ
	RDS(on)3	Vgs = -2.7 V, ID = -2.5 A		52	72	mΩ
	RDS(on)4	Vgs = -2.5 V, ID = -2.5 A		57	77	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		700		pF
Output Capacitance	Coss	V _G S = 0 V		208		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		100		pF
Turn-on Delay Time	td(on)	V _{DD} = −10 V		300		ns
Rise Time	tr	I _D = -2.5 A		528		ns
Turn-off Delay Time	td(off)	$V_{GS(on)} = -4.0 \text{ V}$		242		ns
Fall Time	tf	$R_G = 10 \Omega$		698		ns
Total Gate Charge	QG	Vps = -16 V		6.0		nC
Gate to Source Charge	Qgs	I _D = -4.5 A		2.1		nC
Gate to Drain Charge	Q _{GD}	Vgs = -4.0 V		2.8		nC
Diode Forward Voltage	VF(S-D)	IF = 4.5 A, VGS = 0 V		0.86		V
Reverse Recovery Time	trr	IF = 4.5 A, VGS = 0 V		32		ns
Reverse Recovery Charge	Qrr	$di/dt = 10 A/\mu s$		2.2		nC

TEST CIRCUIT 1 SWITCHING TIME

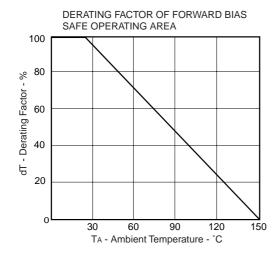
PG. \bigcap Rg \bigvee Rg \bigvee

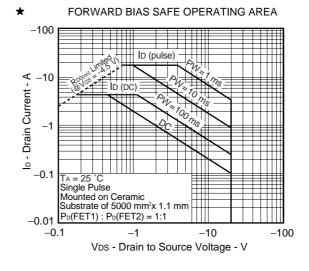
TEST CIRCUIT 2 GATE CHARGE

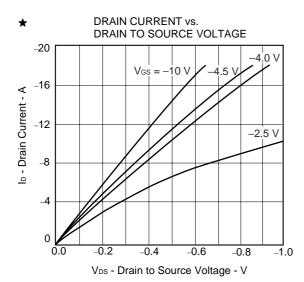


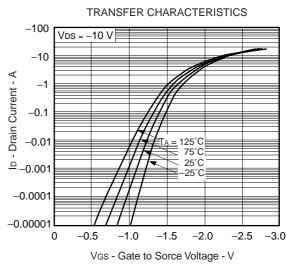


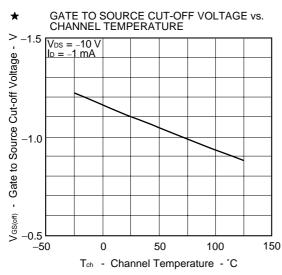
TYPICAL CHARACTERISTICS (TA = 25°C)

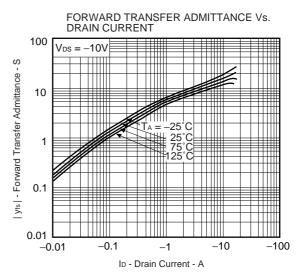




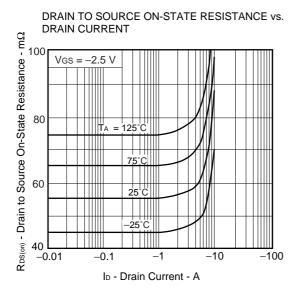


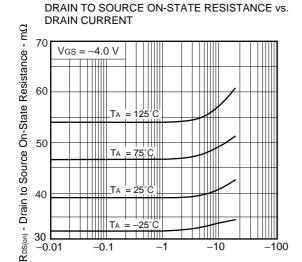




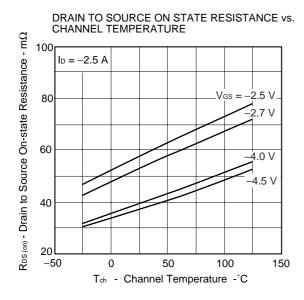


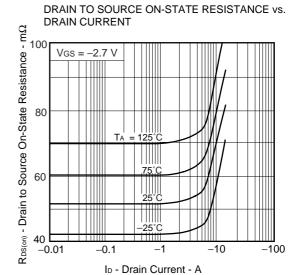
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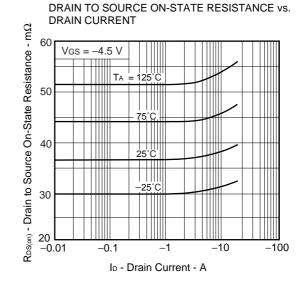


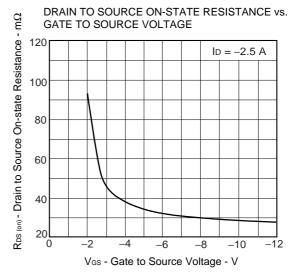


ID - Drain Current - A

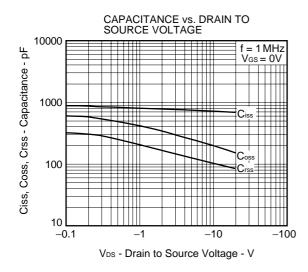


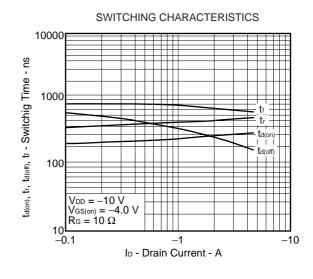




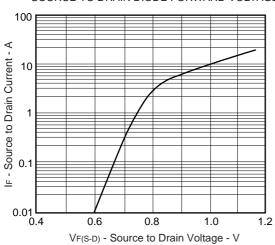


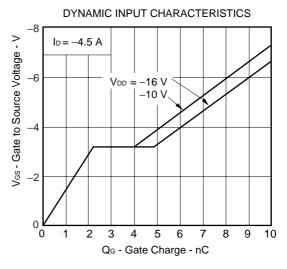




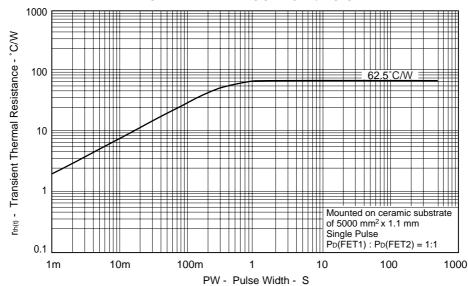








TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH 1000



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[MEMO]

NEC μ PA1856

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 | Control |
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